Unit: mm

TOSHIBA INSULATED GATE BIPOLAR TRANSISTOR SILICON N CHANNEL IGBT

# GT15M321

#### HIGH POWER SWITCHING APPLICATIONS

• Fourth-generation IGBT

• FRD included between emitter and collector

• Enhancement mode type

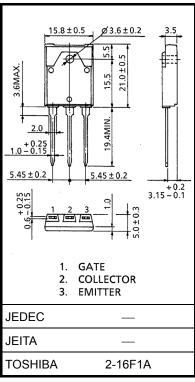
• High speed :  $t_f = 0.20 \mu s$  (TYP.) (IC = 15 A)

• Low saturation voltage : V<sub>CE</sub> (sat) = 1.8V (TYP.)

 $(I_C = 15A)$ 

## ABSOLUTE MAXIMUM RATINGS (Ta=25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Emitter Voltage		V <sub>CES</sub>	900	V	
Gate-Emitter Voltage		V <sub>GES</sub>	±25	V	
Collector Current	DC	IC	15	Α	
	1ms	I <sub>CP</sub>	30		
Emitter-Collector Foward Current	DC	l <sub>F</sub>	15	Α	
	1ms	I <sub>FM</sub>	120		
Collector Power Dissipation (Tc = 25°C)		PC	55	W	
Junction Temperature		Tj	150	°C	
Storage Temperature Range		T <sub>stg</sub>	-55~150	°C	



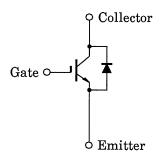
Weight: 5.8 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high

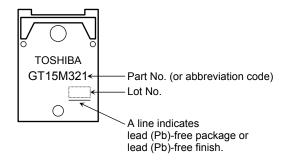
temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **EQUIVALENT CIRCUIT**



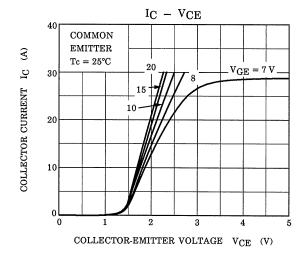
#### **MARKING**

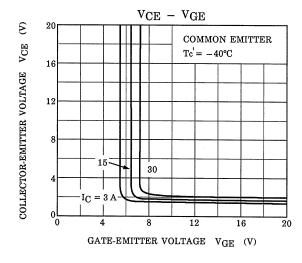


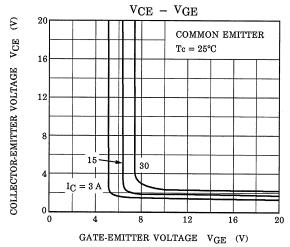
# ELECTRICAL CHARACTERISTICS (Ta=25°C)

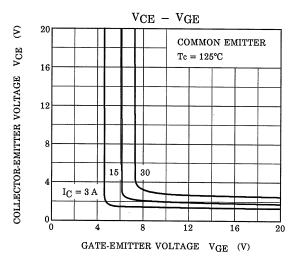
CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Gate Leakage Current		I <sub>GES</sub>	V <sub>GE</sub> = ±25 V, V <sub>CE</sub> = 0	_	_	±500	nA
Collector Cut-off Current		I <sub>CES</sub>	V <sub>CE</sub> = 900 V, V <sub>GE</sub> = 0	_	_	1.0	mA
Gate-Emitter Cut-off Voltage		V <sub>GE</sub> (OFF)	I <sub>C</sub> = 15 mA, V <sub>CE</sub> = 5 V	3.0	_	6.0	V
Collector-Emitter S	aturation Voltage	V <sub>CE</sub> (sat)	I <sub>C</sub> = 15 A, V <sub>GE</sub> = 15 V	_	1.8	2.5	V
Input Capacitance		C <sub>ies</sub>	V <sub>CE</sub> = 10 V, V <sub>GE</sub> = 0, f = 1 MHz	_	1200	_	pF
Switching Time	Rise Time	t <sub>r</sub>	15 V 100 Ω 7 800 V 600 V	_	0.20	_	μs
	Turn-on Time	t <sub>on</sub>		_	0.30	_	
	Fall Time	t <sub>f</sub>		_	0.20	0.40	
	Turn-off Time	t <sub>off</sub>		_	0.50	_	
Emitter-Collector Forward Voltage		V <sub>F</sub>	I <sub>EC</sub> = 15 A, V <sub>GE</sub> = 0	_	1.5	2.0	V
Reverse Recovery Time		t <sub>rr</sub>	I <sub>F</sub> = 15 A, V <sub>GE</sub> = 0 di / dt = -20 A / μs	_	0.7	2.5	μS
Thermal Resistance		R <sub>th (j−c)</sub>	IGBT	_	_	2.27	°C / W
Thermal Resistance		R <sub>th (j-c)</sub>	Diode	_	_	2.27	°C / W

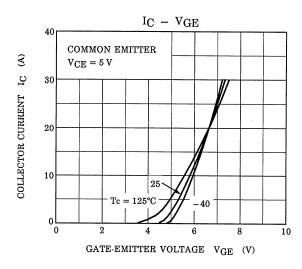
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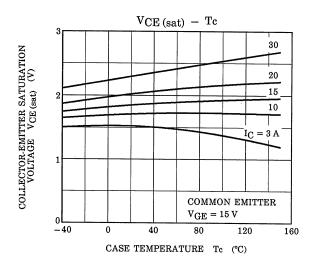




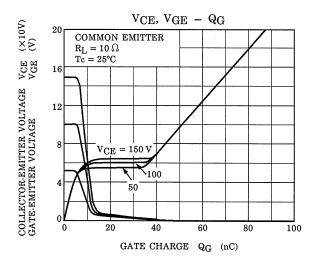


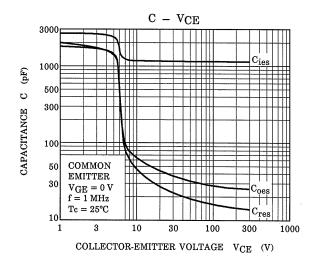


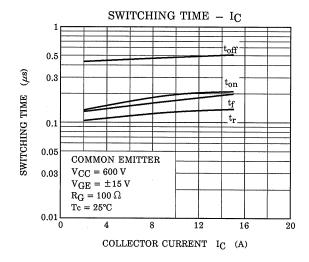


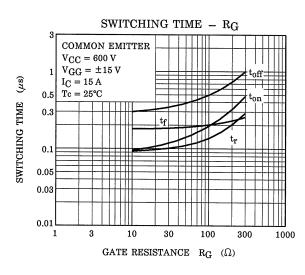


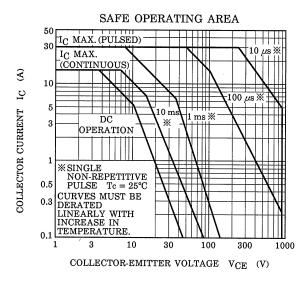
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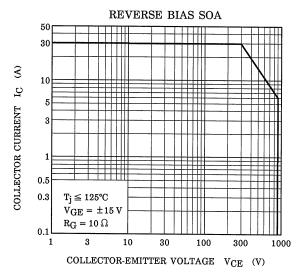


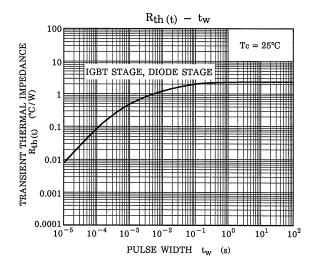


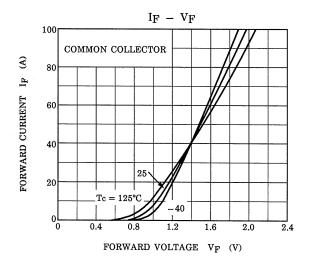


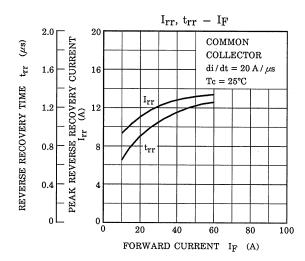


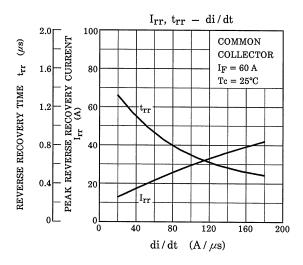


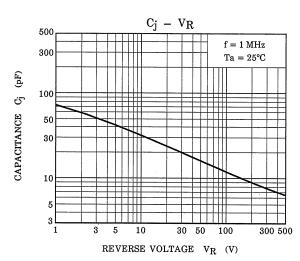












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